TOSHIBA GTR MODULE SILICON N CHANNEL IGBT

## M G 1 5 0 Q 2 Y S 4 0

HIGH POWER SWITCHING APPLICATIONS. MOTOR CONTROL APPLICATIONS.

High Input Impedance

High Speed:  $t_f = 0.5 \mu s$  (Max.)

 $t_{rr} = 0.5 \mu s$  (Max.)

Low Saturation Voltage

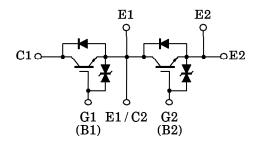
:  $V_{CE(sat)} = 4.0V$  (Max.)

Enhancement-Mode

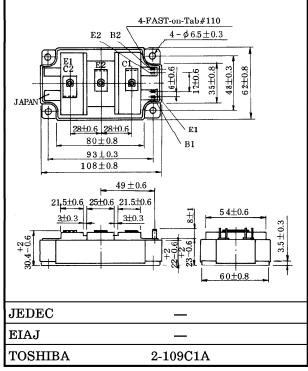
Includes a Complete Half Bridge in One Package.

The Electrodes are Isolated from Case.

## **EQUIVALENT CIRCUIT**



Unit in mm



Weight: 430g

## MAXIMUM RATINGS ( $Ta = 25^{\circ}C$ )

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Emitter Voltage		$v_{CES}$	1200	V	
Gate-Emitter Voltage		$v_{GES}$	±20	V	
Collector Current	DC	$I_{\mathbf{C}}$	150	A	
	1ms	$I_{CP}$	300		
Forward Current	DC	$I_{\mathbf{F}}$	150	A	
	1ms	$I_{\mathbf{FM}}$	300		
Collector Power Dissipation (Tc=25°C)		$P_{\mathbf{C}}$	1100	W	
Junction Temperature		$T_{ m j}$	150	°C	
Storage Temperature Range		$\mathrm{T_{stg}}$	-40~125	°C	
Isolation Voltage		$V_{Isol}$	2500 (AC 1 minute)	V	
Screw Torque (Terminal / Mounting)		_	3/3	N·m	

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## ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		IGES	$V_{GE} = \pm 20V, \ V_{CE} = 0$	-	_	±20	$\mu$ A
Collector Cut-off Current		$I_{CES}$	$V_{CE} = 1200V, V_{GE} = 0$			2.0	mA
Gate-Emitter C	Cut-off Voltage	V <sub>GE(OFF)</sub>	$I_{\text{C}} = 150 \text{mA}, V_{\text{CE}} = 5 \text{V}$	3.0		6.0	V
Collector-Emitter Saturation Voltage		V <sub>CE(sat)</sub>	$I_{C} = 150A, V_{GE} = 15V$	_	3.0	4.0	V
Input Capacitance		Cies	$V_{\text{CE}} = 10\text{V}, V_{\text{GE}} = 0$ f=1MHz		18000	_	pF
Switching Time	Rise Time	$t_r$		-	0.3	0.6	μs
	Turn-on Time	ton	$\begin{bmatrix} 15V & 5.6\Omega \\ 0 & -15V \end{bmatrix} \begin{bmatrix} 3C \\ 0 & 0 \end{bmatrix}$	ı	0.4	0.8	
	Fall Time	$t_f$		-	0.2	0.5	
	Turn-off Time	t <sub>off</sub>	<b>—</b> —15V 600V	1	0.8	1.5	
Forward Voltage V <sub>1</sub>		$ m V_{ m F}$	$I_{F}=150A, V_{GE}=0$	l	2.0	3.0	V
Reverse Recovery Time t <sub>1</sub>		t <sub>rr</sub>	$I_F = 150A, V_{GE} = -10V$ di / dt = 200A / $\mu s$	_	0.25	0.5	μs
Thermal Resistance		$ m R_{th(j-c)}$	Transistor	_	_	0.11	
			Diode	_	_	0.4 C7 W	